International Rectifier

- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- P-Channel
- Fully Avalanche Rated
- Lead-Free

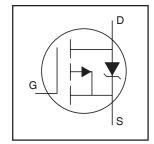
Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

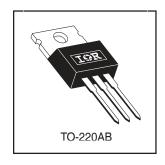
The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

IRF6215PbF

HEXFET® Power MOSFET



$$V_{DSS} = -150V$$
 $R_{DS(on)} = 0.29\Omega$
 $I_{D} = -13A$



Absolute Maximum Ratings

	Parameter	Max.	Units	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ -10V	-13		
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ -10V	-9.0	A	
I _{DM}	Pulsed Drain Current ①	-44		
P _D @T _C = 25°C	Power Dissipation	110	W	
	Linear Derating Factor	0.71	W/°C	
V_{GS}	Gate-to-Source Voltage	± 20	V	
E _{AS}	Single Pulse Avalanche Energy®	310	mJ	
I _{AR}	Avalanche Current①	-6.6	A	
E _{AR}	Repetitive Avalanche Energy①	11	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	-5.0	V/ns	
TJ	Operating Junction and	-55 to + 175		
T _{STG}	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)		
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)		

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.4	
R _{θCS}	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

Electrical Characteristics @ $T_J = 25$ °C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions					
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	-150			V	$V_{GS} = 0V, I_D = 250\mu A$					
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		-0.20		V/°C	Reference to 25°C, I _D = 1mA					
1	0.5 0.0 0.0 0.0			0.29	_	V _{GS} = -10V, I _D = -6.6A ④, T _J = 25°C					
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.58	Ω	V _{GS} = -10V, I _D = -6.6A ④, T _J = 150°C					
V _{GS(th)}	Gate Threshold Voltage	-2.0		-4.0	V	$V_{DS} = V_{GS}$, $I_D = -250\mu A$					
9fs	Forward Transconductance	3.6			S	V _{DS} = -50V, I _D = -6.6A					
1	Drain to Course Leakage Current			-25		V _{DS} = -150V, V _{GS} = 0V					
I _{DSS}	Drain-to-Source Leakage Current			-250	μA	$V_{DS} = -120V, V_{GS} = 0V, T_{J} = 150^{\circ}C$					
	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V					
I _{GSS}	Gate-to-Source Reverse Leakage			-100] ''^ [V _{GS} = -20V					
Qg	Total Gate Charge			66		I _D = -6.6A					
Q _{gs}	Gate-to-Source Charge			8.1	nC	$V_{DS} = -120V$					
Q _{gd}	Gate-to-Drain ("Miller") Charge			35		V_{GS} = -10V, See Fig. 6 and 13 \oplus					
t _{d(on)}	Turn-On Delay Time		14			V _{DD} = -75V					
t _r	Rise Time		36		ns	$I_{D} = -6.6A$					
t _{d(off)}	Turn-Off Delay Time		53] 115	$R_G = 6.8\Omega$					
t _f	Fall Time		37			$R_D = 12\Omega$, See Fig. 10					
L _D	Internal Drain Inductance		4.5			Between lead,					
-υ	memai Brain inductance					4.5			7.0	nH	6mm (0.25in.)
L _S	Internal Source Inductance		7.5		''''	from package					
						and center of die contact					
C _{iss}	Input Capacitance		860			$V_{GS} = 0V$					
Coss	Output Capacitance		220		pF	$V_{DS} = -25V$					
C _{rss}	Reverse Transfer Capacitance		130			f = 1.0MHz, See Fig. 5					

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions	
Is	Continuous Source Current		13		MOSFET symbol		
	(Body Diode)			A	showing the		
I _{SM}	Pulsed Source Current				4.4		integral reverse
	(Body Diode) ①		44		p-n junction diode.		
V _{SD}	Diode Forward Voltage			-1.6	V	$T_J = 25^{\circ}C$, $I_S = -6.6A$, $V_{GS} = 0V$ ④	
t _{rr}	Reverse Recovery Time		160	240	ns	$T_J = 25^{\circ}C, I_F = -6.6A$	
Q _{rr}	Reverse RecoveryCharge		1.2	1.7	μC	di/dt = -100A/µs ⊕	
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)					

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\begin{tabular}{ll} \hline @ Starting $T_J=25^\circ$C, $L=14mH$\\ $R_G=25\Omega, I_{AS}=-6.6A.$ (See Figure 12) \\ \hline \end{tabular}$
- $\begin{tabular}{l} @ I_{SD} \le -6.6A, \ di/dt \le -620A/\mu s, \ V_{DD} \le V_{(BR)DSS}, \\ T_J \le 175 ^{\circ}C \end{tabular}$
- 4 Pulse width \leq 300 μ s; duty cycle \leq 2%.

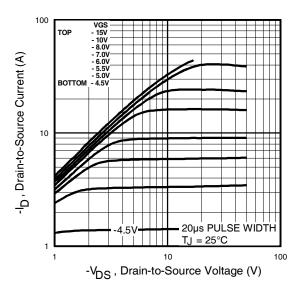


Fig 1. Typical Output Characteristics,

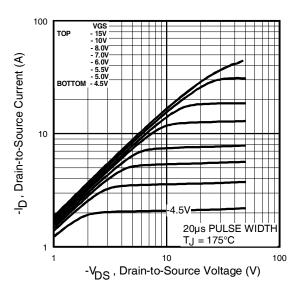


Fig 2. Typical Output Characteristics,

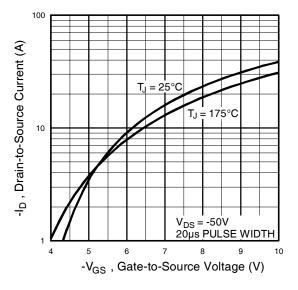


Fig 3. Typical Transfer Characteristics

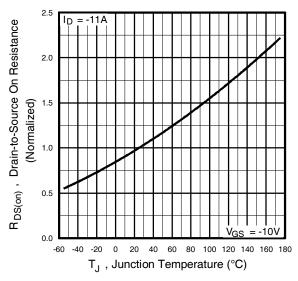


Fig 4. Normalized On-Resistance Vs. Temperature

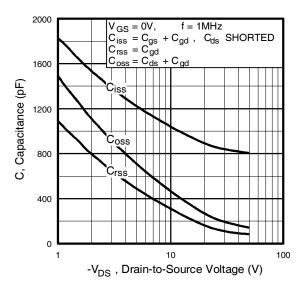


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

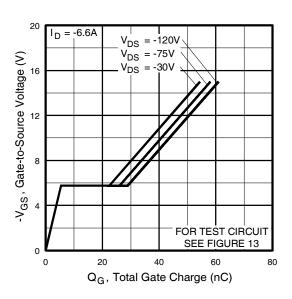


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

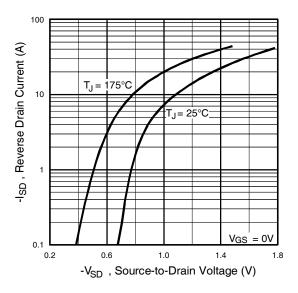


Fig 7. Typical Source-Drain Diode Forward Voltage

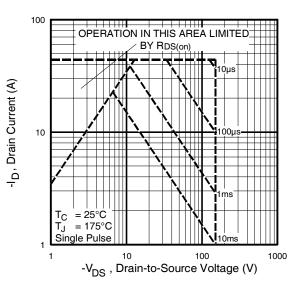


Fig 8. Maximum Safe Operating Area

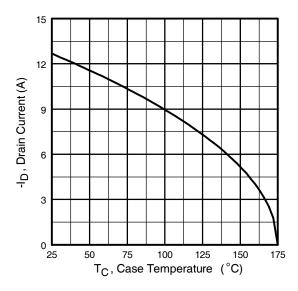


Fig 9. Maximum Drain Current Vs. Case Temperature

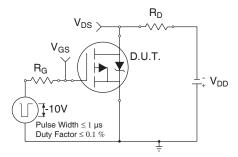


Fig 10a. Switching Time Test Circuit

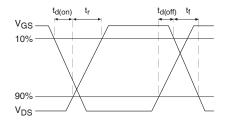


Fig 10b. Switching Time Waveforms

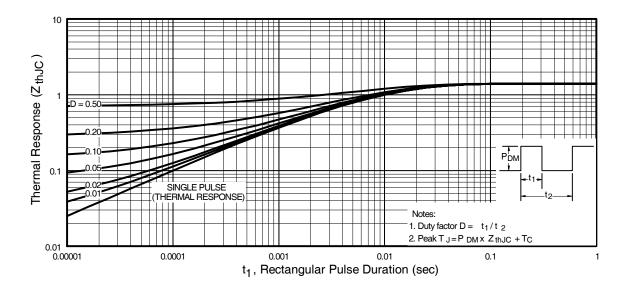


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

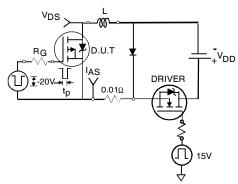


Fig 12a. Unclamped Inductive Test Circuit

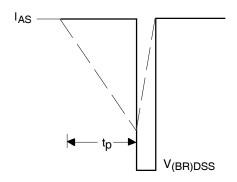


Fig 12b. Unclamped Inductive Waveforms

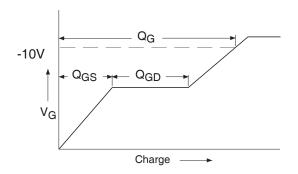


Fig 13a. Basic Gate Charge Waveform

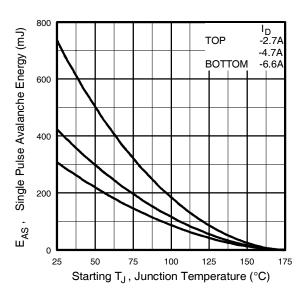


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

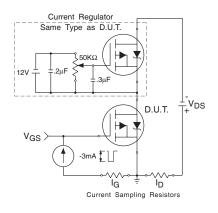
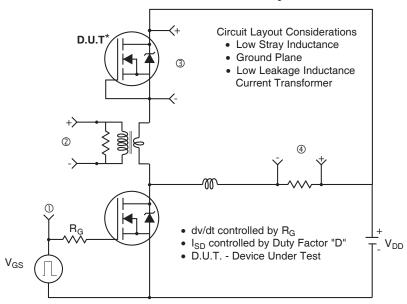
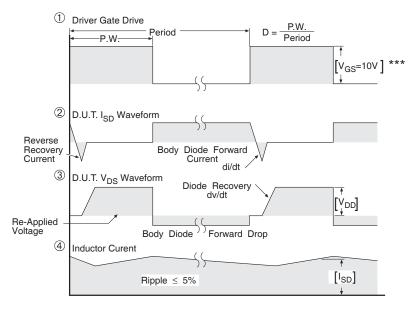


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



^{*} Reverse Polarity of D.U.T for P-Channel

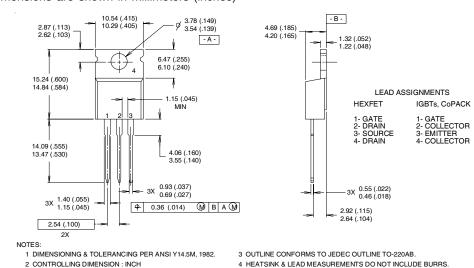


*** $V_{GS} = 5.0V$ for Logic Level and 3V Drive Devices

Fig 14. For P-Channel HEXFETS

TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



TO-220AB Part Marking Information

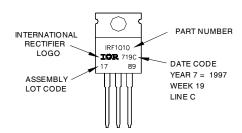
EXAMPLE: THIS IS AN IRF1010

LOT CODE 1789

ASSEMBLED ON WW 19, 1997

IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line
position indicates "Lead-Free"



Data and specifications subject to change without notice.



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Note: For the most current drawings please refer to the IR website at: http://www.irf.com/package/

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